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TRANSMITTAL FORM	Application Number	10/501,276
TRANSMITTAL	Filing Date	July 9, 2004
FORM	First Named Inventor	Johannes F. de Boer et al.
(to be used for all correspondence after initial filing)	Art Unit	2857
	Examiner Name	To be determined
Total Number of Pages in This Submission	Attorney Docket Number	036115/US - 475387-00016

ENCLOSURES (Check all that apply)								
	Fee Transmittal Form  Fee Attached  Amendment/Reply  After Final  Affidavits/declaration(s)  Extension of Time Request  Express Abandonment Request	Drawing(s)  Licensing-related Papers  Petition  Petition to Convert to a Provisional Application Power of Attorney, Revocation Change of Correspondence Address  Terminal Disclaimer  Request for Refund	After Allowance communication to Technology Center (TC)  Appeal Communication to Board of Appeals and Interferences Appeal Communication to TC (Appeal Notice, Brief, Reply Brief)  Proprietary Information  Status Letter  Other Enclosure(s) (please Identify below):  PTO-1449 with 66 references and Return Receipt Postcard					
	Information Disclosure Statement Certified Copy of Priority Document(s) Response to Missing Parts/ Incomplete Application Response to Missing Parts under 37 CFR 1.52 or 1.53	CD, Number of CD(s)						
Firm	SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT							
or Individ	or DORSEY & WHITNEY, LLP Gary Abelev, Esq. (Reg No. 40,479)							
Signature								
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sufficie the dat	I hereby certify that this correspondence is being facsimile transmitted to the USPTO or deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on the date shown below.							
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This collection of information is required by 37 CFR 1.5. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Gary Abelev, Esq.

Signature

036115/US/2 - 475387-00016 PATENT

## UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s)

Johannes F. de Boer et al.

Serial No.

10/501,276

Filed

July 9, 2004

Entitled

APPARATUS AND METHOD FOR RANGING AND NOISE REDUCTION OF LOW COHERENCE INTERFEROMETRY LCI AND OPTICAL COHERENCE TOMOGRAPHY OCT SIGNALS BY PARALLEL DETECTION OF SPECTRAL

**BANDS** 

Group Art Unit

2857

Examiner

To be assigned

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450 I hereby certify that this document is being sent via First Class U. S. mail addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, Virginia 22313-1450 on this day of August 16, 2005.

(Signature)

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(b), applicants bring to the attention of the Examiner the documents listed on the attached Form PTO 1449, and respectfully request that the listed documents be considered by the Examiner and made of record in the above-captioned application. Copies of the United States patent references listed on the Form PTO-1449 are not enclosed, but the PCT, foreign and non-patent references are enclosed.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that the listed documents are material or constitute "prior art." If the Examiner applies the documents as prior art against any claim in the

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application and applicants determine that the cited documents do not constitute "prior art" under

United States law, applicants reserve the right to present to the Office the relevant facts and law

regarding the appropriate status of the documents.

Applicants further reserve the right to take appropriate action to establish the

patentability of the disclosed invention over the listed documents, should the documents be

applied against the claims of the present application.

This submission is being filed before any action by the U.S. Patent and

Trademark Office on the merits. Therefore, applicants do not believe that any fee is due in

connection with the submission of this paper. However, if any fee is due, or if any overpayment

has been made, the Commissioner is authorized to charge any such fee or credit any

overpayment, to our Deposit Account No. 50-2054.

Respectfully submitted,

DORSEY & WHITNEY, LLP

Gary Abelev

PTO Reg. No. 40,479

Attorneys for Applicants

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<sup>\*</sup> Examiner: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Page 2 of 6 Form PTO-1449 U.S. Department of Commerce Atty. Docket No. Serial No. (REV. 2-82) Patent and Trademark Office 036115/US - 475387-00016 10/501,276 INFORMATION DISCLOSURE STATEMENT Applicant(s) BY APPLICANT Johannes F. de Boer (Use several sheets if necessary) Filing Date Group July 9, 2004 2587

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